

# HSP9520, HSP9521

February 1994

# **Multilevel Pipeline Registers**

#### Features

- . Four 8-Bit Registers
- · Hold, Transfer and Load Instructions
- · Single 4-Stage or Dual-2 Stage Pipelining
- · All Register Contents Available at Output
- Fully TTL Compatible
- · Three-State Outputs
- High Speed, Low Power CMOS

# **Applications**

- Array Processor
- · Digital Signal Processor
- A/D Buffer
- Telecommunication
- Byte Wide Shift Register
- Mainframe Computers

# Ordering Information

PART NUMBER	TEMPERATURE RANGE	PACKAGE
HSP9520CP	0°C to +70°C	24 Lead Plastic DIP
HSP9520CS	0°C to +70°C	24 Lead SOIC
HSP9521CP	0°C to +70°C	24 Lead Plastic DIP
HSP9521CS	0°C to +70°C	24 Lead SOIC

## Description

These devices are multilevel pipeline registers implemented using a low power CMOS process. They are pin for pin compatible replacements for industry standard multilevel pipeline registers such as the L29C520 and L29C521. The HSP9520 and HSP5921 are direct replacemens for the AM29520 and AM29521 and WS59520 and WS59521.

They consist of four 8-bit registers which are dual ported. They can be configured as a single four level pipeline or a dual two level pipeline. A single 8-bit input is provided, and the pipelining configuration is determined by the instruction code input to the IO and I1 inputs (see instruction control).

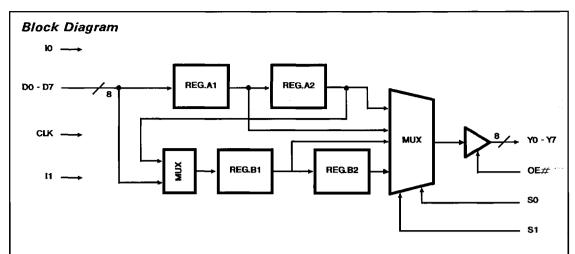
The contents of any of the four registers is selectable at the multiplexed outputs through the use of the S0 and S1 multiplexer control inputs (see register select). The output is 8-bits wide and is three-stated through the use of the OE# input.

The HSP9520 and HSP9521 differ only in the way data is loaded into and between the registers in dual two-level operation. In the HSP9520 when data is loaded into the first level the existing data in the first level is moved to the second level. In the HSP9521 loading the first level simply causes the current data to be overwritten. Transfer of data to the second level is achieved using the single four level mode (I1, 10 = '0'). This instruction also causes the first level to be loaded. The HOLD instruction (I1, I0 = '1') provides a means of holding the countents of all registers.

## **Pinout**

#### HSP9520, HSP9521 (24 PIN SOIC, NPDIP) TOP VIEW

11 2 23 SO 22 S1 D0 3 21 YO D1 4 20 Y1 D3 6 19 Y2 D4 7 18 Y3 D5 8 17 Y4 D6 9 16 Y5 D7 10 15 Y6 CLK 11 14 Y7 GND 12 13 OE#



# Pin Descriptions

NAME	DIP PIN	TYPE	DESCRIPTION
vcc	24		The +5V power supply pin. A $0.1\mu F$ capacitor between the $V_{CC}$ and GND pin is recommended.
GND	12		The device ground.
CLK	11	1	Input Clock. Data is latched on the low to high transition of this clock signal. Input setup and hold times with respect to the clock must be met for proper operation.
D0-7	3-10	1	Data Input Port. These inputs are used to supply the 8 bits of data which will be latched into the selected register on the next rising clock edge.
Y0-7	21-14	0	Data Output Port. This 8-bit port provides the output data from the four internal registers. They are provided in a multiplexed fashion, and are controlled via the multiplexer control inputs (S0 and S1).
10, 11	1,2	i	Instruction Control Inputs. These inputs are used to provide the instruction code which determines the internal register pipeline configuration. Refer to the Instruction Control Table for the specific codes and their associated configurations.
S0, S1	23, 22	ı	Multiplexer Control Inputs. These Inputs select which of the four internal registers' contents will be available at the output port. Refer to the Register Select Table for the codes to select each register.
OE#	13	I	Output Enable. This input controls the state of the output port (Y0-Y7). A LOW on this control line enables the port for ouput. When OE# is HIGH, the output drivers are in the high impedance state. Internal latching or transfer of data is not affected by this pin.

### Specifications HSP9520/HSP9521

# Absolute Maximum Ratings Operating Conditions Supply Voltage +8.0V Input or Output Voltage Applied GND -0.5V to V<sub>CC</sub> +0.5V Storage Temperature Range -65°C to +150°C Junction Temperature +150°C Lead Temperature (Soldering, Ten Seconds) +300°C Maximum Package Power Dissipation 1.5W (DIP), 1.0W (SOIC)

# D.C. Electrical Specifications (V<sub>CC</sub> = 5.0V $\pm$ 5%, T<sub>A</sub> = 0°C to +70°C)

PARAMETER	SYMBOL	MIN	MAX	UNITS	TEST CONDITIONS
Logical One Input Voltage	VIH	2.0	_	V	V <sub>CC</sub> = 5.25V
Logical Zero Input Voltage	VIL	_	0.8	V	V <sub>CC</sub> = 4.75V
Output HIGH Voltage	V <sub>ОН</sub>	2.4	-	٧	I <sub>OH</sub> = -6.5mA, V <sub>CC</sub> = 4.75V
Output LOW Voltage	VOL	_	0.5	٧	I <sub>OL</sub> = +20.0mA, V <sub>CC</sub> = 4.75V
Input Leakage Current	il	-10	10	μА	$V_{IN} = V_{CC}$ or GND, $V_{CC} = 5.25V$
Output Leakage Current	10	-10	10	μА	V <sub>OUT</sub> = V <sub>CC</sub> or GND V <sub>CC</sub> = 5.25V
Standby Power Supply Current	ICCSB	-	500	Ąц	V <sub>IN</sub> = V <sub>CC</sub> or GND V <sub>CC</sub> = 5.25V Outputs Open
Operating Power Supply Current	ІССОР	-	12	mA	f = 5.0MHz, V <sub>IN</sub> = V <sub>CC</sub> or GND V <sub>CC</sub> = 5.25V, Ouputs Open, Note 1

# Capacitance ( $T_A = +25$ °C, Note 3)

PARAMETER	SYMBOL	MIN	MAX	UNITS	TEST CONDITIONS	
Input Capacitance	CIN	-	12	pF	FREQ = 1 MHz, V <sub>CC</sub> = Open, all measuremen	
Output Capacitance	со	-	12	pF	are referenced to device ground.	

# A.C. Electrical Specifications ( $V_{CC} = 5.0V \pm 5\%$ , $T_A = 0^{\circ}C$ to +70°C, Note 2)

PARAMETER	SYMBOL	MIN	MAX	UNITS	TEST CONDITIONS (Note 2)
Clock to Data Out	T <sub>PD</sub>	-	21	ns	
Mux Select to Data Out	TSELD	-	20	ns	
Input Setup Time (D0-7/I0-7)	TS	10	-	ns	
Input Hold Time (D0-7/I0-7)	тн	3	-	ns	
Output Enable Time	TENA	-	20	ns	
Output Disable Time	TDIS	-	13	ns	Note 3
Clock Pulse Width	TpW	10		ns	

#### NOTES:

- 1. Power supply current is proportional to frequency. Typical rating for  $I_{\mbox{\footnotesize{CCOP}}}$  is 2.4mA/MHz.
- 2. A.C. Testing is performed as follows: Input levels: OV and 3.0V, Timing reference levels = 1.5V, Input rise and fall times driven at 1ns/V, Output load C<sub>L</sub> = 40pF.
- 3. Controlled by design or process parameters and not directly tested. Characterized upon initial design and after major design and/or process changes.

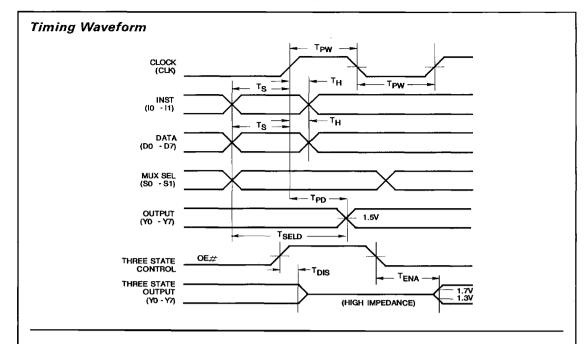


TABLE 1. INSTRUCTION CONTROL

11 10 '9520 '9521 **A**1 В1 A1 В1 0 0 A2 B2 **A2** B2 **A1 B**1 **A1** В1 0 1 A2 В2 A2 B2 A1 В1 **A**1 В1 0 **A2** В2 A2 B2 1 ALL REGISTERS HOLD ALL REGISTERS HOLD

TABLE 2. REGISTER SELECT

<b>S1</b>	S0	'9520 OR '9521
0	0	B2
0	1	B1
1	0	A2
1	1	A1